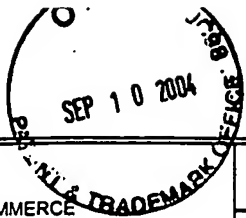


FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Date Submitted: September 10, 2004		ATTY DOCKET NO. 03500.018000		APPLICATION NO. 10/808,481			
		APPLICANT Naoya Kawamura, et al.					
		FILING DATE March 25, 2004		GROUP 1745			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/LW/		5,800,939	09/01/1998	Mishina et al.	429	57	
		5,998,063	12/07/1999	Kobayashi et al.	429	218.1	
		6,558,848 B1	05/06/2003	Kobayashi et al.	429	241	
		6,517,974 B1	02/11/2003	Kobayashi et al.	429	231.95	
		6,569,568 B2	05/27/2003	Kobayashi et al.	429	221	
		6,372,387 B1	04/16/2002	Kawakami et al.	429	303	
		6,377,030 B1	04/23/2002	Asao et al.	320	161	
		6,558,847 B1	05/06/2003	Kawakami et al.	429	231.95	
		5,824,434	10/20/1998	Kawakami et al.	429	209	
		5,491,037	02/13/1996	Kawakami	429	49	
		5,882,811	03/16/1999	Kawakami	429	49	
/LW/		5,702,845	12/30/1997	Kawakami et al.	429	224	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/LW/		11-283627	10/15/1999	JAPAN			Abstract
/LW/		2000-311681	11/07/2000	JAPAN			Abstract
/LW/		WO 00/17949	03/30/2000	PCT			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER /Laura Weiner/				DATE CONSIDERED 06/17/2007			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



FORM PTO 1449 (modified)		ATTY DOCKET NO. 03500.018000		APPLICATION NO. 10/808,481			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT Naoya Kawamura, et al.					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE March 25, 2004		GROUP 1745			
Date Submitted: September 10, 2004							
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/LW/		5,728,482	03/17/1998	Kawakami et al.	429	10	
		5,888,666	03/30/1999	Kawakami	429	62	
		6,051,340	04/18/2000	Kawakami et al.	429	231.95	
		6,596,432 B2	07/22/2003	Kawakami et al.	429	60	
		5,641,591	06/24/1997	Kawakami et al.	429	218	
		5,698,339	12/16/1997	Kawakami et al.	429	212	
		6,063,142	05/16/2000	Kawakami et al.	29	623.5	
		6,165,642	12/26/2000	Kawakami et al.	429	218.1	
		6,638,322 B1	10/28/2003	Kawakami et al.	29	623.1	
		5,658,689	08/19/1997	Kawakami et al.	429	194	
		5,919,589	07/06/1999	Kawakami et al.	429	231.8	
/LW/		6,329,096 B2	12/11/2001	Kawakami et al.	429	49	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/LW/		2000-215887	08/04/2000	JAPAN			Abstract
/LW/		2002-352797	12/06/2002	JAPAN			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER /Laura Weiner/				DATE CONSIDERED 06/17/2007			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SEP 10 2004
U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

FORM PTO 1449 (modified)

ATTY DOCKET NO. 03500.018000 APPLICATION NO. 10/808,481

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

APPLICANT Naoya Kawamura, et al.

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted: September 10, 2004 FILING DATE March 25, 2004 GROUP 1745

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/LW/	6,432,585 B1	08/13/2002	Kawakami et al.	429	233	
	6,730,434 B1	05/04/2004	Kawakami et al.	429	218.1	
	6,475,664 B1	11/05/2002	Kawakami et al.	429	137	
	6,649,304 B2	11/18/2003	Tani et al.	429	223	
	5,795,679	08/18/1998	Kawakami et al.	429	218	
	6,383,686 B1	05/07/2002	Umeno et al.	429	231.8	
	2003/0143464 A1	07/31/2003	Yamamoto et al.	429	231.95	
	2002/0015889 A1	02/07/2002	Yamamoto et al.	429	231.95	
	2002/0197530 A1	12/26/2002	Tani et al.	429	218.2	
	2003/0157407 A1	08/21/2003	Kosuzu et al.	429	231.95	
/LW/	2002/0055041 A1	05/09/2002	Kobayashi et al.	429	221	

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

--	--	--

EXAMINER /Laura Weiner/ DATE CONSIDERED 06/17/2007

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

